


<b>Search Notes</b> 	<b>Application/Control No.</b> 10814081	<b>Applicant(s)/Patent Under Reexamination</b> CHOU ET AL.
	<b>Examiner</b> ERIC YEN	<b>Art Unit</b> 2626

SEARCHED			
Class	Subclass	Date	Examiner
704	9	10/8/08	EY

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--